

Search Notes

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Examiner

Nam Huynh

Applicant(s)/Patent under
Reexamination

VANDER VEEN ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
379	142.01- 142.09	11/27/2006	NTH
709	1-6	11/27/2006	NTH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See EAST search notes.	11/27/2006	NTH